SDFS012A - D3214, JANUARY 1989 - REVISED OCTOBER 1993

 Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs

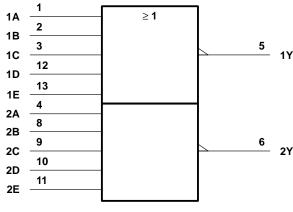
# description

The SN74F260 contains two independent 5-input positive-NOR gates. It performs the Boolean functions Y = A + B + C + D + E in positive logic.

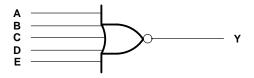
The SN74F260 is characterized for operation from  $0^{\circ}$ C to  $70^{\circ}$ C.

#### D OR N PACKAGE (TOP VIEW) 1A 14 V<sub>CC</sub> 1B 13**∏** 1E 2 12 1D 1C 3 2A 11∏ 2E 10 2D 1Y 2Y 9 2C 6 вП **GND** 2B

# logic symbol†



# logic diagram, each gate (positive logic)



# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	1.2 V to 7 V
Input current range	30 mA to 5 mA
Voltage range applied to any output in the high state	$\dots$ -0.5 V to V <sub>CC</sub>
Current into any output in the low state	40 mA
Operating free-air temperature range	0°C to 70°C
Storage temperature range	. −65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input voltage ratings may be exceeded provided the input current ratings are observed.



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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## recommended operating conditions

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	V
٧ıH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
Ικ	Input clamp current			-18	mA
lOH	High-level output current			- 1	mA
loL	Low-level output current			20	mA
TA	Operating free-air temperature	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS			TYP <sup>†</sup>	MAX	UNIT
VIK	$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$			-1.2	V
Vou	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -1 \text{ mA}$	2.5	3.4		٧
VOH	$V_{CC} = 4.75 V$ ,	$I_{OH} = -1 \text{ mA}$	2.7			
V <sub>OL</sub>	$V_{CC} = 4.5 \text{ V},$	$I_{OL} = 20 \text{ mA}$		0.3	0.5	V
lį	$V_{CC} = 5.5 \text{ V},$	V <sub>I</sub> = 7 V			0.1	mA
liH	$V_{CC} = 5.5 V$ ,	V <sub>I</sub> = 2.7 V			20	μΑ
I <sub>IL</sub>	$V_{CC} = 5.5 V$ ,	V <sub>I</sub> = 0.5 V			- 0.6	mA
I <sub>OS</sub> ‡	$V_{CC} = 5.5 V$ ,	V <sub>O</sub> = 0	-60		-150	mA
Іссн	$V_{CC} = 5.5 V$ ,	V <sub>I</sub> = 0		4.6	6.5	mA
ICCL	$V_{CC} = 5.5 \text{ V},$	V <sub>I</sub> = 4.5 V		7.3	9.5	mA

<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

# switching characteristics (see Note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C <sub>I</sub> R <sub>I</sub>	CC = 5 V _ = 50 pl _ = 500 s _ = 25°C	F, Ω,	V <sub>CC</sub> = 4.5 C <sub>L</sub> = 50 p R <sub>L</sub> = 5009 T <sub>A</sub> = MIN	Ω,	UNIT
			MIN	TYP	MAX	MIN	MAX	
t <sub>PLH</sub>	A, B, C, D, E		1.7	4	5.5	1.2	6.5	ns
<sup>t</sup> PHL		1	1	2.5	4	1	4.5	115

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 2: Load circuits and waveforms are shown in Section 1.



<sup>‡</sup> Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

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